

# DTP4N80/DTP4N80F/DTU4N80/DTL4N80

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## **Power MOSFET**

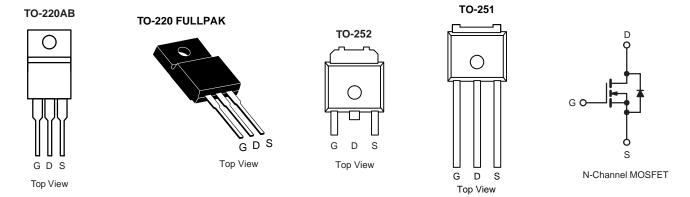
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	800			
$R_{DS(on)}(\Omega)$	V <sub>GS</sub> = 10 V	3.2		
Q <sub>g</sub> (Max.) (nC)	19			
Q <sub>gs</sub> (nC)	4			
Q <sub>gd</sub> (nC)	9			
Configuration	Single			

### **FEATURES**

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement
- Enhanced 30 V, V<sub>GS</sub> Rating
- Reduced C<sub>iss</sub>, C<sub>oss</sub>, C<sub>rss</sub>
- Extremely High Frequency Operation
- Repetitive Avalanche Rated
- Compliant to RoHS Directive 2002/95/EC







### DTL4N80 DTP4N80 ..... 'DTP4N80F DTU4N80

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-Source Voltage		V <sub>DS</sub>	800	V	
Gate-Source Voltage			$V_{GS}$		
Continuous Drain Current	V <sub>GS</sub> at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	l <sub>D</sub>	4	
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C		2.9	Α
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	16	
Linear Derating Factor			1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	128	mJ
Repetitive Avalanche Current <sup>a</sup>			I <sub>AR</sub>	6.2	Α
Repetitive Avalanche Energy <sup>a</sup>			E <sub>AR</sub>	13	mJ
Maximum Power Dissipation	Power Dissipation $T_C = 25  ^{\circ}C$			150	W
Peak Diode Recovery dV/dtc			dV/dt	5.0	V/ns
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	- °C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 <sup>d</sup>	
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in
				1.1	N · m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b.  $V_{DD} = 50$  V, starting  $T_J = 25$  °C, L = 25 mH,  $R_g = 25$   $\Omega$ ,  $I_{AS} = 6.2$  A (see fig. 12). c.  $I_{SD} \le 6.2$  A, dl/dt  $\le 80$  A/µs,  $V_{DD} \le V_{DS}$ ,  $T_J \le 150$  °C.

- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	62	
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	1.0	

SPECIFICATIONS (T <sub>J</sub> = 25 °C, u	nless otherw	ise noted)					
PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0$	V, I <sub>D</sub> = 250 μA	800	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	to 25 °C, I <sub>D</sub> = 1 mA	-	0.75	-	V/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V$	<sub>GS</sub> , I <sub>D</sub> = 250 μA	2.5	-	4.5	V
Gate-Source Leakage	I <sub>GSS</sub>	V	$V_{GS} = \pm 20$		-	± 100	nA
Zovo Coto Voltago Drain Current	,	$V_{DS} = 80$	00 V, V <sub>GS</sub> = 0 V	-	-	50	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 480 V, \	/ <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	100	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	$I_D = 3.7 \text{ Ab}$	-	3.2	4	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 10	00 V, I <sub>D</sub> = 3.7 A <sup>b</sup>	3.7	-	-	S
Dynamic							
Input Capacitance	C <sub>iss</sub>	$V_{GS} = 0 V$ $V_{DS} = 25 V$		=	679	-	pF
Output Capacitance	C <sub>oss</sub>			-	55	-	
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0	f = 1.0 MHz, see fig. 5		9	-	
Total Gate Charge	Qg			-	-	39	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V	$I_D = 4 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and 13 <sup>b</sup>	-	-	10	
Gate-Drain Charge	Q <sub>gd</sub>		335 iigi 5 aii a	=	-	19	
Turn-On Delay Time	t <sub>d(on)</sub>			-	12	-	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 300 V, $I_D$ = 4 A $R_g$ = 9.1 Ω, $R_D$ = 47 Ω, see fig. 10 <sup>b</sup>		-	20	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>			-	27	-	
Fall Time	t <sub>f</sub>			-	17	-	
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	الم
Internal Source Inductance	L <sub>S</sub>			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	cs					•	,
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	4.0	Α
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>			-		16	A
Body Diode Voltage	V <sub>SD</sub>	$T_J = 25$ °C, $I_S = 4$ A, $V_{GS} = 0$ $V^b$		-	-	1.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 25  ^{\circ}\text{C}, \ I_{F} = 4  \text{A}, \ \text{dI/dt} = 100  \text{A/}\mu\text{s}^{-\text{b}}$		-	440	680	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	2.1	3.2	μC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is domi			minated b	y L <sub>S</sub> and	L <sub>D</sub> )

### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width  $\leq$  300  $\mu$ s; duty cycle  $\leq$  2 %.

## TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

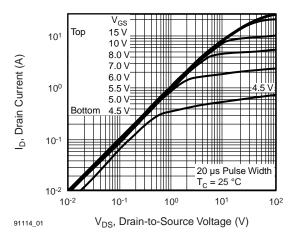


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

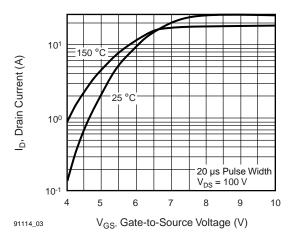


Fig. 3 - Typical Transfer Characteristics

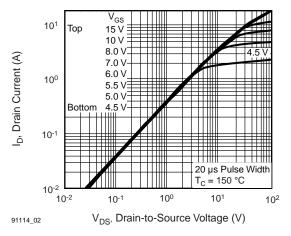


Fig. 2 - Typical Output Characteristics, T<sub>C</sub> = 150 °C

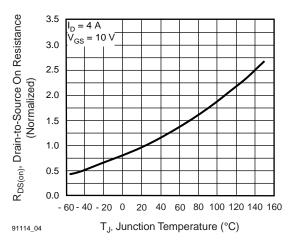


Fig. 4 - Normalized On-Resistance vs. Temperature



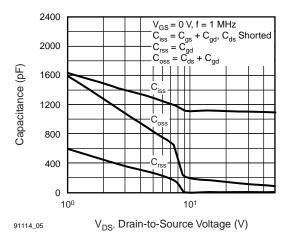


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

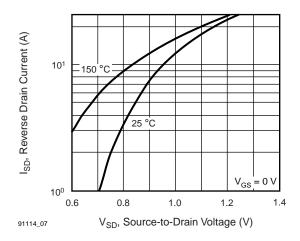


Fig. 7 - Typical Source-Drain Diode Forward Voltage

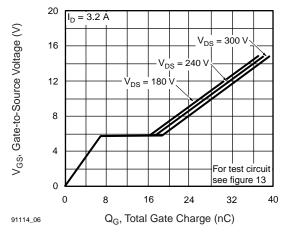


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

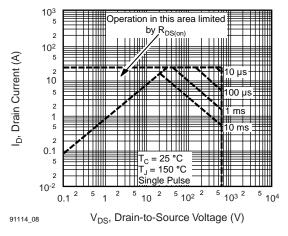


Fig. 8 - Maximum Safe Operating Area

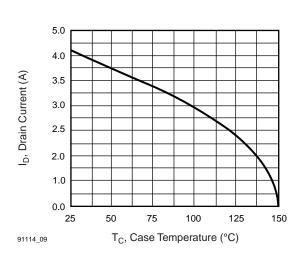


Fig. 9 - Maximum Drain Current vs. Case Temperature

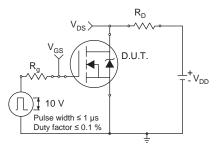


Fig. 10a - Switching Time Test Circuit

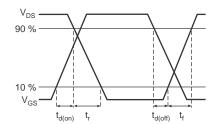


Fig. 10b - Switching Time Waveforms

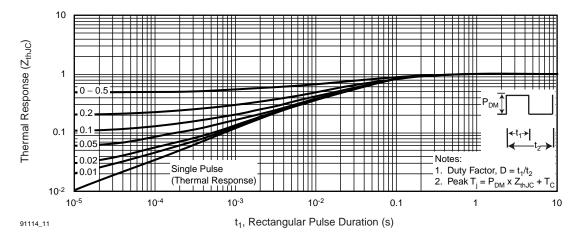


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

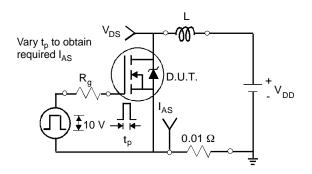


Fig. 12a - Unclamped Inductive Test Circuit

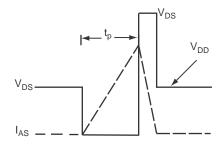


Fig. 12b - Unclamped Inductive Waveforms

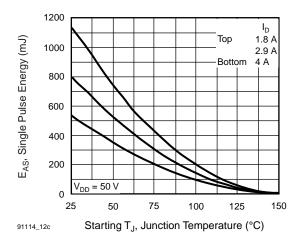


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

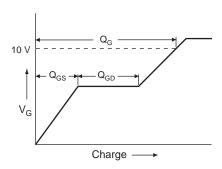


Fig. 13a - Basic Gate Charge Waveform

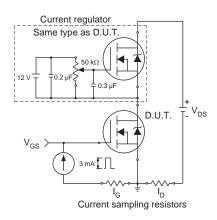


Fig. 13b - Gate Charge Test Circuit





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